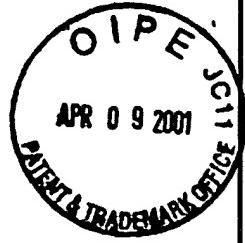


**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**



Applicant(s): MEHRDAD NIKOONAHAD, GUOHENG ZHAO, ANDREI V.  
SHCHEGROV and BEN TSAI  
Assignee: KLA-TENCOR TECHNOLOGIES CORPORATION  
Title: OVERLAY ERROR DETECTION  
Serial No.: 09/697,025 Filing Date: October 26, 2000  
Examiner: Unknown Group Art Unit: 2623  
Docket No.: M-10697 US

San Jose, California  
April 4 2001

COMMISSIONER FOR PATENTS  
Washington, D. C. 20231

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Applicants wish to call the enclosed documents to the attention of the Examiner. A PTO form 1449 listing these documents is enclosed.

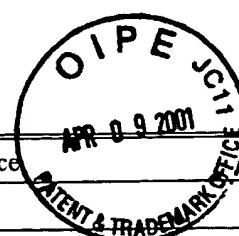
Citation of the above documents shall not be construed as:

1. an admission that the documents are necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on <u>APRIL 4, 2001</u> .	
Tammy L. Kaplan	Date of Signature <u>4/4/01</u>
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Respectfully submitted,

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Reg. No. 29,545



U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Serial No.
		M-10697 US	09/697,025
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Applicant(s)	
(Use several sheets if necessary)		MEHRDAD NIKOONAHAD ET AL.	
		Filing Date	Group
		October 26, 2000	2623

## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,023,338	2/8/2000	Bareket	356	401	7/12/96
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## Foreign Patent Documents

Translation

		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	"Microinterferometre differentiel a ondes polarises," G. Nomarski, <i>J. Phys Radium</i> 16, (S-13S (1955))
	AR	"Lithography Process Control," H. Levinson, <i>SPIE press</i> , Vol. TT28, Bellingham, Washington, 1999
	AS	

Examiner Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.